JOINT INDUSTRY STANDARD

Space and Military
Applications Electronic
Hardware Addendum to
IPC J-STD-001H
Requirements for
Soldered Electrical
and Electronic
Assemblies

IPC J-STD-001HS April 2021

Supersedes IPC J-STD-001GS-AM1 January 2020





The Principles of Standardization

In May 1995 the IPC's Technical Activities Executive Committee (TAEC) adopted Principles of Standardization as a guiding principle of IPC's standardization efforts.

Standards Should:

- Show relationship to Design for Manufacturability (DFM) and Design for the Environment (DFE)
- · Minimize time to market
- Contain simple (simplified) language
- Just include spec information
- Focus on end product performance
- Include a feedback system on use and problems for future improvement

Standards Should Not:

- Inhibit innovation
- Increase time-to-market
- Keep people out
- Increase cycle time
- Tell you how to make something
- Contain anything that cannot be defended with data

Notice

IPC Standards and Publications are designed to serve the public interest through eliminating misunderstandings between manufacturers and purchasers, facilitating interchangeability and improvement of products, and assisting the purchaser in selecting and obtaining with minimum delay the proper product for his particular need. Existence of such Standards and Publications shall not in any respect preclude any member or nonmember of IPC from manufacturing or selling products not conforming to such Standards and Publication, nor shall the existence of such Standards and Publications preclude their voluntary use by those other than IPC members, whether the standard is to be used either domestically or internationally.

Recommended Standards and Publications are adopted by IPC without regard to whether their adoption may involve patents on articles, materials, or processes. By such action, IPC does not assume any liability to any patent owner, nor do they assume any obligation whatever to parties adopting the Recommended Standard or Publication. Users are also wholly responsible for protecting themselves against all claims of liabilities for patent infringement.

IPC Position
Statement on
Specification
Revision Change

It is the position of IPC's Technical Activities Executive Committee that the use and implementation of IPC publications is voluntary and is part of a relationship entered into by customer and supplier. When an IPC publication is updated and a new revision is published, it is the opinion of the TAEC that the use of the new revision as part of an existing relationship is not automatic unless required by the contract. The TAEC recommends the use of the latest revision.

Adopted October 6, 1998

Why is there a charge for this document?

Your purchase of this document contributes to the ongoing development of new and updated industry standards and publications. Standards allow manufacturers, customers, and suppliers to understand one another better. Standards allow manufacturers greater efficiencies when they can set up their processes to meet industry standards, allowing them to offer their customers lower costs.

IPC spends hundreds of thousands of dollars annually to support IPC's volunteers in the standards and publications development process. There are many rounds of drafts sent out for review and the committees spend hundreds of hours in review and development. IPC's staff attends and participates in committee activities, typesets and circulates document drafts, and follows all necessary procedures to qualify for ANSI approval.

IPC's membership dues have been kept low to allow as many companies as possible to participate. Therefore, the standards and publications revenue is necessary to complement dues revenue. The price schedule offers a 50% discount to IPC members. If your company buys IPC standards and publications, why not take advantage of this and the many other benefits of IPC membership as well? For more information on membership in IPC, please visit www.ipc.org or call 847/597-2809.

Thank you for your continued support.



IPC J-STD-001HS

Space and Military
Applications Electronic
Hardware Addendum to
IPC J-STD-001H
Requirements for
Soldered Electrical and
Electronic Assemblies

Developed by the J-STD-001 Space and Military Electronic Assemblies Task Group (5-22as) of the Assembly & Joining Committee (5-20) of IPC

Supersedes:

IPC J-STD-001GS-AM1 -January 2020 IPC J-STD-001GS -March 2018 IPC J-STD-001FS WAM1 -January 2017 IPC J-STD-001FS -January 2015 Users of this publication are encouraged to participate in the development of future revisions.

Contact:

IPC 3000 Lakeside Drive, Suite 105N Bannockburn, Illinois 60015-1249 Tel 847 615.7100 Fax 847 615.7105



Acknowledgment

Any document involving a complex technology draws material from a vast number of sources across many continents. While the principal members of these task groups are shown below, it is not possible to include all of those who assisted in the evolution of this standard. To each of them, the members of IPC extend their gratitude.

Assembly and Joining Committee

J-STD-001 Space and Military Electronic Assemblies Task Group **Technical Liaison of the IPC Board of Directors**

Chair

Vice Chair

Daniel L. Foster

Missile Defense Agency

NASA Marshall Space Flight Center Vice Chair

Garry D. McGuire

Karen Tellefsen Ekaterina Stees
MacDermid Alpha Electronics Lockheed Martin Missiles &

Solutions Fire Control

Bob Neves

Microtek (Changzhou) Laboratories

Members of J-STD-001 Space and Military Electronic Assemblies Task Group*

Kathy Johnston

Moriah Bischann

Douglas Schueller, AbelConn, LLC

Neil Wolford, AbelConn, LLC

Ross Dillman, ACI Technologies, Inc.

Constantino Gonzalez, ACME
Training & Consulting

John Vickers, Advanced Rework Technology - A.R.T.

Debbie Wade, Advanced Rework Technology - A.R.T.

Michael Wierleski, Aerojet Rocketdyne

Brandy Tharp, AeroTEC Inc.

Chris Stuber, American Hakko Products Inc.

Sean Keating, Amphenol Limited (UK)

Stefan Hanigk, Ariane Group GmbH

Greg Hurst, BAE Systems

Joseph Kane, BAE Systems

Kelly Kovalovsky, BAE Systems

Agnieszka Ozarowski, BAE Systems

Jonathon Vermillion, Ball Aerospace

& Technologies Corp.

Gerald Bogert, Bechtel Plant

Machinery, Inc.

Samuel Sorto, Blue Origin, LLC

Ryan Trussell, Blue Origin, LLC

Eric Harenburg, Boeing Company

Dawn Cabales, Carlisle Interconnect Technologies

Tawsha Cabales, Carlisle Interconnect Technologies

Vesna Delic, Carlisle Interconnect Technologies

Steven Perng, Cisco Systems Inc.

Robert Priore, Cisco Systems Inc.

David Adams, Collins Aerospace

William Cardinal, Collins Aerospace

Caroline Ehlinger, Collins Aerospace

David Hillman, Collins Aerospace

Scott Meyer, Collins Aerospace

Timothy Pearson, Collins Aerospace

Miguel Dominguez, Continental Temic SA de CV

Jose Servin Olivares, Continental Temic SA de CV

Kathleen Kouthong, Crane Aerospace & Electronics

Symon Franklin, Custom Interconnect Ltd

Monica Tucker, Dynetics, Inc.

Gil Zilber, Elta Systems Ltd.

Murilo Levy Casotti, Embraer SA

Leo Lambert, EPTAC Corporation

Marcia McLaughlin, EPTAC Corporation

Helena Pasquito, EPTAC Corporation

Kenneth Rahn, FCI USA, Inc.

Francisco Fourcade, Fourcad, Inc

Henrik Jensen, Gaasdal Bygningsindustri A/S

Melby Muckom, General Dynamics

Advanced Information Systems

Francesco Di Maio, GESTLABS S.r.l.

Lalith Bandara, GPV Lanka (Pvt) Ltd.

John Mastorides, Honeywell Aerospace

Christina Rutherford, Honeywell Aerospace

Hector Valladares, Honeywell Aerospace

Keith Walker, Honeywell Aerospace

Richard Rumas, Honeywell Canada

Milea Kammer, Honeywell International

Jennie Hwang, H-Technologies Group

Joe Hughes, Hughes Circuits, Inc.

Poul Juul, HYTEK

Ana Ferrari Felippi, Instituto de Pesquisas Eldorado

Ife Hsu, Intel Corporation

Jose Luis Gonella, INVAP S.E.

Emmanuelle Guene, Inventec Performance Chemicals

Toshiyasu Takei, Japan Unix Co., Ltd.

- Jose Delgado, Jet Propulsion Laboratory
- Minh Do, Jet Propulsion Laboratory
- Reza Ghaffarian, Jet Propulsion Laboratory
- Alan Young, Jet Propulsion Laboratory
- Sue Powers-Hartman, Killdeer Mountain Manufacturing, Inc.
- Nancy Bullock-Ludwig, Kimball Electronics
- Augustin Stan, L&G Advice Serv SRL
- Shelley Holt, L3Harris Communications
- Theodore Laser, L3Harris Communications
- Peter Menuez, L3Harris Technologies, Inc.
- Dominik Alder, Lockheed Martin Corporation
- Chris Newton, Lockheed Martin Corporation
- Don Dupriest, Lockheed Martin Missiles & Fire Control
- Ben Gumpert, Lockheed Martin Missiles & Fire Control
- Sharissa Johns, Lockheed Martin Missiles & Fire Control
- Kyle Johnson, Lockheed Martin Missiles & Fire Control
- Vijay Kumar, Lockheed Martin Missiles & Fire Control
- Pamela Petcosky, Lockheed Martin Mission Systems & Training
- Owen Reid, Lockheed Martin Missiles & Fire Control
- Ekaterina Stees, Lockheed Martin Missiles & Fire Control
- Ann Marie Tully, Lockheed Martin Missiles & Fire Control
- Jarrod Webb, Lockheed Martin Missiles & Fire Control
- Schuyler Williams, Lockheed Martin Missiles & Fire Control

- David Mitchell, Lockheed Martin Rotary & Mission Systems
- Paul Kirpes, Los Alamos National Laboratory
- Matt Garrett, Microsemi
- Daniel Foster**, Missile Defense Agency (MDA)
- Edward Rios, Motorola Solutions
- Alvin Boutte, NASA Goddard Space Flight Center
- Chris Fitzgerald, NASA Goddard Space Flight Center
- Bhanu Sood, NASA Goddard Space Flight Center
- Robert Cooke, NASA Johnson Space Center
- James Blanche, NASA Marshall Space Flight Center
- Charles Gamble, NASA Marshall Space Flight Center
- Adam Gowan, NASA Marshall Space Flight Center
- Garry McGuire, NASA Marshall Space Flight Center
- Zackary Fava, NAVAIR
- William May, Naval Surface Warfare Ctr
- Joseph Sherfick, Naval Surface Warfare Ctr
- Nicholas Walton, Naval Surface Warfare Ctr
- Stephanie Stork, Northrop Grumman
- Randy McNutt, Northrop Grumman Aerospace Systems
- Patrick Phillips, Northrop Grumman Innovation Systems
- Ceferino Reyes, Northrop Grumman Innovation Systems
- Mahendra Gandhi, Northrop Grumman Space Systems
- Kelly Wrightsman, Northrop Grumman SSES
- Callie Olague, Northrop Grumman Systems Corporation
- William Graver, NTS Baltimore

- Bruce Hughes, Nvidia Corporation
- Gustavo Arredondo, PARA TECH Parylene Services
- Rob Walls, PIEK International Education Centre (I.E.C.) BV
- Kirk Van Dreel, Plexus Corp.
- James Taylor, Plexus Corp.
- Philip Henault, Raytheon
- James Daggett, Raytheon Company
- Mary Herndon, Raytheon Company
- Michael Jawitz, Raytheon Company
- Lisa Maciolek, Raytheon Company
- David Pinsky, Raytheon Company
- James Saunders, Raytheon Company
- Fonda Wu, Raytheon Company
- Matthew Abbott, Raytheon Missile Systems
- Lance Brack, Raytheon Missile Systems
- Maria Colon, Raytheon Missile Systems
- George Millman, Raytheon Missile Systems
- Joseph Schmidt, Raytheon Missile Systems
- Nichole C. Thilges, Raytheon Missile Systems
- Martin Scionti, Raytheon Vision Systems
- Rama Murthy PBV, Research Centre Imarat, DRDO, Ministry of Defence
- Chris Mahanna, Robisan Laboratory Inc.
- Gary Latta***, SAIC
- Rodney Doss, Samtec, Inc.
- Scott Vorhies, Space Exploration Technologies
- Jay Brusse, SSAI at NASA Goddard Space Flight Center
- Robert Fornefeld, STI Electronics, Inc.
- Patricia Scott, STI Electronics, Inc. Lynda Pelley, Teledyne Dalsa

Michael Collier, Teledyne Leeman Labs

Gaston Hidalgo, Toyota Motor North America

Daniel Koss, TTM Technologies, Inc.

James Monarchio, TTM

Technologies, Inc.

Tapas Yagnik, TTM Technologies, Inc.

Paul Zutter, U.S. Army Aviation & Missile Command

Constantin Hudon, Varitron Technologies Inc.

Dave Harrell, Viasat Inc.

Lorna Stoddart, WL Gore &
Associates (UK) Ltd

Zhiman Chen, Zhuzhou CRRC Times
Electric Co., LTD.

Zhe (Jacky) Liu, ZTE Corporation

^{*} Members of the Space Electronic Assemblies J-STD-001 Addendum Task Group (5-22as) and Requirements for Military Systems Working Group (5-22ad) of the Assembly and Joining Processes Committee (5-20) merged their activities during the development of this document and are now known as 5-22as J-STD-001 Space and Military Electronic Assemblies Task Group.

^{**} Chair, 5-22ad, Requirements for Military Systems Working Group prior to merging with 5-22as.

^{***}Vice Chair, 5-22ad, Requirements for Military Systems Working Group prior to merging with 5-22as.

This Page Intentionally Left Blank

Space and Military Applications Electronic Hardware Addendum to IPC J-STD-001H Requirements for Soldered Electrical and Electronic Assemblies

Table of Contents

The following topics are addressed in this Addendum.

- 0.1 Scope
- 0.1.1 Purpose
- 0.1.2 Precedence
- 0.1.3 Existing or Previously Approved Designs
- 0.1.4 Use
- 0.1.5 Red Plague (Cuprous Oxide Corrosion)
- 0.1.6 Materials and Processes Traceability

Table of Contents for Table 1 Space and Military Applications Requirements

1.1	Scope	
1.2	Purpose	
1.5.3.2	High Frequency Applications	
1.5.3.3	High Voltage Applications	
1.6.2	Statistical Process Control	
1.7	Order of Precedence	
1.10	Personnel Proficiency	
1.11	Acceptance Requirements	
1.12.2	Inspection	
3.1	Materials	
3.2	Solder	
3.2.1	Solder – Pb – Free	
3.3	Flux	
3.6.1	Component and Seal Damage	
4.3	Removal of Component Surface Finishes	
4.3.1	Gold Removal	
4.5	Rework of Nonsolderable Parts	
4.7	General Part Mounting Requirements	
4.7.2	Lead Deformation Limits	
4.13.3	Drying/Degassing	
4.15.1	Exposed Surfaces	
4.15.2	Solder Connection Anomalies	
4.15.3	Partially Visible or Hidden Solder Connections	
5.1.2	Strand Damage	
5.3.6	Terminal Mounting – Soldering	
5.5	Soldering to Terminals	
5.6.3	Wire Staking	

6.1	Through-Hole Terminations - General	
6.1.1	Lead Forming	
6.1.2	Termination Requirements	
6.2.2	Through-Hole Component Lead Soldering	
6.3.1	Lead Termination Requirements for Unsupported Holes	
7.0	Surface Mounting of Components	
7.1.2	Forming	
7.1.3	Unintentional Bending	
7.5.5	Cylindrical End Cap Terminations	
7.5.6	Castellated Terminations	
7.5.7	Flat Gull Wing Leads	
7.5.8	Round or Flattened (Coined) Gull Wing Leads	
7.5.14	Surface Mount Area Array Packages	
7.5.15	Bottom Termination Components (BTC)	
7.5.16	Components with Bottom Thermal Plane Terminations (D-Pak)	
7.5.17	Flattened Post Connections	
7.5.19	Vertical Cylindrical Cans with Outward L-Shaped Lead Terminations	
7.5.20	Wrapped Terminals	
8.0	Cleaning and Residue Requirements	
8.1	Qualified Manufacturing Process	
8.1.1	Cleaning Designator	
8.3.1	Level 1 – Major Changes Requiring Validation	
8.4	Foreign Object Debris (FOD)	
8.5	Visible Residues	
9.1.1	Blistering/Delamination	
9.1.2	Weave Exposure/Cut Fibers	
9.1.9	Burns	
9.1.11	Measles	
10.0	Coating, Encapsulation, Staking and Bonding	
10.1.3	Application	
10.1.11	Rework or Touchup	
10.3.1.2	Staking – Application – SMT	
10.4 [NEW]	Bonding (Adhesive)	
12.2	Repair	

1

0.1 Scope This Addendum provides requirements to be used in addition to, and in some cases, in place of, those published in J-STD-001H to ensure the reliability of soldered electrical and electronic assemblies that must survive the vibration and thermal cyclic environments in space and military applications.

- **0.1.1 Purpose** When required by procurement documentation/engineering documentation, this Addendum supplements or replaces specifically identified requirements of J-STD-001H.
- **0.1.2 Precedence** The contract takes precedence over this Addendum, referenced standards and User-approved drawings. In the event of a conflict between this Addendum and the applicable documents cited herein, this Addendum takes precedence. Where referenced criteria of this Addendum differ from the published J-STD-001H, this Addendum takes precedence. In the event of conflict between the requirements of this Addendum and the applicable assembly drawing(s)/documentation, the applicable User approved assembly drawing(s)/documentation take precedence. See Table 1 of this Addendum 1.7 Order of Precedence.
- **0.1.3 Existing or Previously Approved Designs** This Addendum **shall not** constitute the sole cause for the redesign of previously approved designs. When drawings for existing or previously approved designs undergo revision, they should be reviewed and changes made that allow for conformance with the requirements of this Addendum.
- **0.1.4 Use** This Addendum is not to be used as a stand-alone document.

Where criteria are not modified through change or addition, the Class 3 requirements of J-STD-001H **shall** apply. Where J-STD-001H criteria are altered or new criteria are added by this Addendum, the clause is listed in J-STD-001HS, Table 1, Space and Military Applications Requirements, and the entire J-STD-001H clause is replaced by this Addendum except as specifically noted. Clauses found only in this Addendum will have "[NEW]" after the clause number in the table.

Clauses, Tables, Figures, etc., in J-STD-001H that are not listed in this Addendum shall be used as-published.

0.1.5 Red Plague (Cuprous Oxide Corrosion) Red Plague can develop in silver-coated soft or annealed copper conductors (component leads, single and multistranded wires and printed board conductors) when a galvanic cell forms between the copper base metal and the silver coating in the presence of moisture (H2O) and oxygen (O2). Once initiated, the sacrificial corrosion of the copper base conductor can continue indefinitely in the presence of oxygen. The color of the corrosion by-product (cuprous oxide crystals) may vary depending on the different levels of oxygen available, but is commonly noted as a red/reddish-brown discoloration on the silver coating surface.

The use of silver coating over any form of copper, e.g., component leads, printed board traces, wire/cable **shall** require the implementation of a User-approved Red Plague Control Plan (RPCP). See IPC-WP-113, Guidance for the Development and Implementation of a Red Plague Control Plan (RPCP), for technical guidance and a generic RPCP template.

0.1.6 Materials and Processes Traceability When required, the traceability of materials and processes used in the manufacture of electrical/electronic hardware **shall** be in compliance with IPC-1782, Standard for Manufacturing and Supply Chain Traceability of Electronic Products. Traceability Level **shall** be determined between the Manufacturer and the User.

		pace and Military Appli	
J-STD-001H Reference	Space and Military Applications Requirements (as changed by this Addendum)		
1.1	Scope This Standard describes materials, methods and acceptance criteria for producing soldered electrical ar electronic assemblies. The intent of this document is to rely on process control methodology to ensure consiste quality levels during the manufacture of products. It is not the intent of this Standard to exclude any procedure from component placement or for applying flux and solder used to make the electrical connection.		
			I in this document are based on electrical/electronic ications listed in J-STD-001HS Table 1-1.
	J-STD-001HS_Table	1-1 Design, Fabrication	and Acceptability Specifications
	Board Type	Design	Fabrication/Acceptability Specification
	Generic Requirements	IPC-2221	IPC-6011
	Rigid Printed Boards	IPC-2222	IPC-6012 Space & Military Addendum
	Flexible Circuits	IPC-2223	IPC-6013
	Rigid Flex Board	IPC-2223	IPC-6013
1.2	Note: This clause is unchanged from and Military Applications Addendum do		ided here to clarify that the Purpose of the Space r the Purpose of the base document.
	for the manufacture of soldered electric document's recommendations and required	cal and electronic asser uirements, one may use s may be updated at an	ocess requirements, and acceptability requirements mblies. For a more complete understanding of this this document in conjunction with IPC-HDBK-001, y time, including with the addition of amendments. Illy required.
1.5.3.2	clearances, mounting systems, and ass frequency design requirements preven	sembly designs which va t compliance with the o	i.e., radio wave and microwaves, may require part ary from the requirements stated herein. When high design and part mounting requirements contained alternative designs' acceptance criteria shall be
1.5.3.3	High Voltage Applications High voltage applications may require part clearances, mounting systems, and assembly designs which vary from the requirements stated herein. When such design requirements prevent compliance with the design and part mounting requirements contained herein, Manufacturers may use alternative designs. These alternative designs' acceptance criteria shall be approved by the User prior to use.		
1.6.2	 Statistical Process Control The use of statistical process control is encouraged but not mandatory, see 1.6 Process Control Requirements. When a statistical process control system process is used, it shall include the following elements as a minimum: a. Training is provided to personnel with assigned responsibilities in the development, implementation, and utilization of process control and statistical methods that are commensurate with their responsibilities. b. Quantitative methodologies and evidence is maintained to demonstrate that the process is capable and in control. Improvement strategies define initial process control limits and methodologies leading to a reduction in the occurrence of process indicators in order to achieve continuous process improvement. c. Sampling inspection shall be prohibited unless approved by the User prior to use. d. When sampling is pre-approved by the User, any defect(s) identified in the lot sample exceeding the limit(s allowed by the sampling plan, requires the entire lot to be 100% inspected for the occurrence(s) of the identified defect(s). e. A system is in place to initiate corrective action(s) for the occurrence of process indicators, out-of-control process(es), and/or discrepant assemblies. f. A documented audit plan is defined to monitor process characteristics and/or output at a prescribed frequency objective evidence of process control may be in the form of control charts or other tools and techniques of statistical process control derived from application of process parameter and/or product parameter data, see IPC-HDBK-001. 		
1.7	dards and User approved drawings, see In the event of conflict between the documentation, the applicable User a documentation include the contract, purpose specification. In the event of a cited herein, the text of this standard to standard and an assembly drawing(s)/See 0.1.2 Precedence of this Addendumentation when J-STD-001 is cited or required to	requirements of this sipproved assembly drawarchase order, technical conflict between the teakes precedence. In the documentation that has lim. by contract, the requirem of or other related documents of the contract of th	tandard and the applicable assembly drawing(s)/wing(s)/documentation govern. Some examples of data package, engineering specification or perforext of this standard and the applicable documents event of conflict between the requirements of this not been User approved, this standard governs. The provided Head of the provide

J-STD-001H Reference	Space and Military Applications Requirements (as changed by this Addendum)
1.10	Personnel Proficiency All instructors, operators, and inspection personnel shall be proficient in the tasks to be performed. Objective evidence, e.g., records of training to the applicable job functions being performed, work experience, testing to the requirements of this Addendum, or results of periodic reviews on proficiency shall be maintained and be available for review.
	Training shall be in accordance with the J-STD-001 Training and Certification Program or a Manufacturer developed program that shall be made available for review and approval upon request by the User. All training shall be traceable to a J-STD-001 Master IPC Trainer (MIT).
1.11	Acceptance Requirements All products shall meet the requirements of the assembly drawing(s)/documentation and the requirements specified herein.
	Unless otherwise specified in the contract, Manufacturers shall perform 100% inspection (see 1.6.2.c Statistical Process Control of this Addendum) using either visual inspection or nondestructive evaluation (NDE). Nondestructive verification techniques shall be approved by the User prior to use.
	The User has the responsibility to specify acceptance criteria. If no criteria are specified, criteria shall be established and agreed upon between the Manufacturer and User.
1.12.2	Inspection After the soldering and cleaning process is complete, all assemblies shall be evaluated by 100% visual or by nondestructive inspection. Nondestructive inspection requires User approval per 1.11 Acceptance Requirements of this Addendum, including solder connections as specified in 4.15.3 Partially Visible or Hidden Solder Connections, 7.5.14 Surface Mount Area Array Packages, 7.5.15 Bottom Termination Components (BTC), and 7.5.16 Components with Bottom Thermal Plane Terminations (D-Pak), and 7.5.19 Vertical Cylindrical Cans with Outward L-Shaped Lead Terminations of this Addendum.
	When assemblies are to be conformally coated and/or staked or encapsulated, the coating, encapsulation, and/or staking shall be evaluated by 100% visual inspection. Inspection of soldering and cleanliness shall be performed prior to all conformal coating operations, and any staking or encapsulation operations that prevent visual access to solder connections.
3.1	Materials The materials and processes used to assemble/manufacture electronic assemblies shall be selected such that their use, in combination, produce products acceptable to this standard.
	When an element of the proven process is changed which may affect the form, fit, or function of the final product, e.g., flux, solder paste, cleaning media or system, solder alloy or soldering system, validation of the change(s) shall be performed and documented. Acceptance criteria for the tests shall be agreed upon between the Manufacturer and User. Implementation of the change(s) shall be approved by the User prior to use. Element changes may also pertain to a change in bare boards (including supplier), solder mask, or metallization.
	Limited shelf life items shall be stored and controlled in accordance with material supplier's recommendations or in accordance with the Manufacturer's documented procedures for controlling shelf life. Limited shelf life items shall be traceable, e.g., lot number, date code and/or expiration date.
	Solders, component leads, and all other surfaces containing Pb-free tin as defined in 3.2.1 Solder - Pb-Free of this Addendum, shall be processed in accordance with 3.2.1 Solder - Pb-Free of this Addendum.
3.2	Solder Solder alloys shall be Sn60Pb40, Sn62Pb36Ag2, Sn63Pb37, or Sn96.3Ag3.7 in accordance with J-STD-006 or User approved equivalent standard. Other solder alloys that provide the service life, performance, and reliability required of the product may be used if all other conditions of this standard are met and objective evidence of such is reviewed and approved by the User prior to use. High temperature solder alloys, e.g., Sn96.3Ag3.7, shall only be used where specifically indicated by approved drawings. Flux that is part of flux-cored solder wire or solder paste shall meet the requirements of 3.3 Flux of this Addendum. Flux percentage is optional.
3.2.1	Solder – Pb-Free For the purpose of this document, Pb-free tin is defined as pure tin or any tin alloy containing less than 3% Pb by weight as an alloying constituent.
	The use of Pb-free tin solder alloys/Pb-free tin for either the assembly of, or existing on, the external surfaces (platings, metallization, etc.) of components, sub-assemblies, packaging technologies, mechanical hardware shall be prohibited unless documented and controlled through a User approved Pb-Free Control Plan (LFCP).
	Solder alloy Sn96.3Ag3.7 is exempt from this requirement, i.e., inclusion in a User approved LFCP is not required. See 3.2 Solder of this Addendum.

J-STD-001H Reference	Space and Military Applications Requirements (as changed by this Addendum)	
3.3	Flux Flux shall be in accordance with J-STD-004 or User approved equivalent standard. Flux shall conform to flux activity levels L0 or L1 of flux materials rosin (RO) or resin (RE). When other activity levels or flux materials are used, data demonstrating material and process compatibility through testing agreed upon between the Manufacturer and User shall be provided. Use of any other flux shall be approved by the User prior to use.	
	Note: Flux or soldering process combinations previously tested or qualified in accordance with other specifications do not require additional testing.	
	Type H or M fluxes may be used for tinning of insulated solid wires with insulation bonded to the wire, e.g., magnet wire.	
	When an external flux is used in conjunction with flux cored solders, the fluxes shall be compatible.	
	For all fluxing applications where adequate cleaning is not practical, only flux types RO or RE of the LO flux activity level, or equivalent, shall be used.	
3.6.1	Component and Seal Damage Minor surface flaws, discoloration, meniscus cracks, or chips in component bodies are acceptable. However, they shall not expose the component substrate or active element nor affect structural integrity. Components shall not be charred. Component damage in excess of that determined to be a minor surface flaw shall not degrade the component below the part specification requirements, or as otherwise determined, to meet form, fit, function and life expectancy requirements. This may be determined through documented analysis.	
4.3	Removal of Component Surface Finishes Certain surface finishes on component terminations or printed board lands may impact the quality of the solder connection.	
	Under either of the following conditions, the printed boards or parts are exempt from the requirements for finish removal stated in 4.3.1 Gold Removal of this Addendum and J-STD-001H 4.3.2 Other Metallic Surface Finishes Removal:	
	• If there is documented objective evidence, available for review and approved by the User prior to use, that there are no gold related solder embrittlement issues, or other metallic surface finish solder joint integrity problems, e.g., with Sn or SnBi, associated with the soldering process being used, see IPC-HDBK-001 or IPC-AJ-820 handbook for guidance.	
	• For electroless nickel immersion gold (ENIG), nickel-palladium-gold (NiPdAu), or electroless nickel electroless palladium immersion gold (ENEPIG) finishes.	
4.3.1	Gold Removal Except as noted in 4.3 Removal of Component Surface Finishes of this Addendum, gold shall be removed from at least 95% of the surfaces to be soldered of all component leads, component terminations, and solder terminals. A double tinning process or dynamic solder wave may be used for gold removal prior to mounting the component on the assembly.	
4.5	Rework of Nonsolderable Parts A component lead, termination, or board not conforming to the solderability requirements of 4.1 Solderability may be reworked, e.g., by dipping in hot solder, before soldering.	
	A reworked part shall conform to the requirements of 4.1 Solderability, less conditioning.	
4.7	General Part Mounting Requirements When design restrictions mandate mounting components incapable of withstanding soldering temperatures incident to a particular process, such components shall be mounted and soldered to the assembly as a separate operation.	
	If cleaning is required, parts should be mounted with sufficient clearances between the body and the printed board to assure adequate cleaning and cleanliness testing. Assemblies should be cleaned after each soldering operation so that subsequent placement and soldering operations are not impaired by contamination.	
	Parts should be mounted such that part markings and reference designators are visible, see 9.2 Marking.	
	Minimum electrical clearance shall not be violated.	
	When sleeving is required as protection for glass, ceramic, or hermetic components that will be coated, encapsulated or staked, the sleeving shall be placed on the component prior to installation.	
	Uninsulated parts mounted over exposed circuitry or which are in close proximity with other conductive materials shall be separated by suitable insulation.	
	There shall be a documented process for torquing of threaded fasteners, including, but not limited to, standard torque values (when not specified in other engineering documentation), workmanship requirements, installation procedures, quality assurance provisions, and tool control.	
	When components are mounted to the assembly using fasteners, the fasteners shall be tightened/torqued prior to soldering.	
4.7.2	Lead Deformation Limits Leads shall not have any nicks, scrapes or gouges. Smooth indentations up to 10% of the diameter, width, or thickness of the lead, e.g., tooling marks, and as allowed for intentionally flattened leads, are acceptable. See 4.15.1 Exposed Surfaces of this Addendum, 4.5 Rework of Nonsolderable Parts of this Addendum, and 7.1.6 Flattened Leads.	

J-STD-001H Reference	Space and Military Applications Requirements (as changed by this Addendum)			
4.13.3	Drying/Degassing Prior to soldering, the printed board shall be treated to remove moisture and other volations using a documented process.			
	Treated assemblies/printed boards do not need to be re-treated if they are stored in a controlled atmosphere 5% RH or less prior to any subsequent soldering operations.			
	Note: See IPC-1602 for further information on moisture sensitive printed boards.			
4.15.1	Exposed Surfaces Except as noted elsewhere in J-STD-001H or this Addendum, the following requirement apply to exposed surfaces:			
	 a. Exposed basis metal shall not prevent the formation of an acceptable solder connection. b. Exposed Organic Solderability Preservatives (OSP) shall not prevent the formation of an acceptable sold connection. c. Iron based material, e.g., Alloy 42, Kovar®, shall not be exposed on component leads or bodies. 			
4.15.2	Solder Connection Anomalies The following solder joint conditions shall be considered defects:			
4.13.2	 a. Fractured solder connections. b. Disturbed solder connections. c. Incomplete reflow of solder paste. d. Cold or rosin solder connections. e. Evidence of dewetting that causes the solder connection to not meet the solder fillet requirements. f. Solder has not wetted to the land or termination where solder is required. 			
	 g. Solder that violates minimum electrical clearance. h. Solder that contacts the component body (except as noted in other clauses). i. Does not comply with wetting criteria of J-STD-001H 4.15 Solder Connection. j. Solder bridging except when path is present by design. k. Blowholes and pinholes (where the bottom and all sides are not visible). l. Solder that obscures the stress relief bend of through-hole components. (Solder in the bend radius is r for rejection provided the lead is properly formed, the topside bend radius is discernible, and the so not extend to within 1 lead diameter of the part body or end seal). 			
4.15.3	Partially Visible or Hidden Solder Connections Partially visible or hidden solder connections shall meet to			
	 following conditions: a. The design does not restrict solder flow to any connection element on the solder destination side lands, PTH component, of the assembly. b. The visible portion, if any, of the connection on either side of the PTH solder connection (or the visible po of the SMD connection) is acceptable. c. Process controls are maintained in a manner assuring acceptable and repeatable process results. 			
	For solder connections that do not meet any of the above conditions, NDE shall be used. For nondestructive evaluation, see 1.11 Acceptance Requirements of this Addendum.			
5.1.2	Strand Damage J-STD-001H Table 5-1 does not apply; there shall be no nicked, scraped or broken w strands. See 4.7.2 Lead Deformation Limits of this Addendum for damage requirements applicable to solid coductor wires/leads.			
	For plated wires, a visual anomaly that does not expose basis metal is not considered to be strand damage.			
	Smooth indentations such as tooling marks up to 10% are allowed.			
	Disturbed wire strands should be restored to approximate their original lay.			
	Wire strands shall not have separation exceeding one strand diameter or extend beyond wire insulation outside diameter.			
	Wire strands shall not be altered or cut to fit terminals.			
5.3.6	Terminal Mounting – Soldering Terminals mounted and soldered to the printed board shall meet the requirements shown in Table 5-2 of this Addendum.			
	Table 5-2 Terminal Mounting Minimum Soldering Requirements			
	0000			
	A. Circumferential fillet and wetting – solder source side 360°			

J-STD-001H Reference	Space and Military Applications Requirements (as changed by this Addendum)	
5.5	Soldering to Terminals A solder fillet shall join the wire/lead to the terminal for 100% of the lead to te contact area.	
	Wetted solder depression in the lead/wire to terminal contact area shall not be more than 25% R. See J-STD-001HS Figure 5-1.	
	A	
	25%R - 25%R	
	 R	
	J-STD-001HS Figure 5-1 Solder Depression A. Maximum R. Radius	
5.6.3	Wire Staking Staking applied to wires shall not be allowed to touch any moving parts. Staking should be applied such that it is sufficient to secure the wire with no spillover onto component leads above the foot, adjacent lands, component bodies, or end seals that may be sensitive, e.g., glass, ceramic. Wires longer than 25 mm [1 in] shall be staked at intervals not more than 25 mm [1 in] and at every change of direction.	
	Staking material shall not overhang the board edge(s) or violate edge spacing requirements. Staking adhesive, when used, shall comply with 10.0 Coating, Encapsulation, Staking and Bonding of this Addendum.	
6.1	Through-Hole Terminations – General Axial leaded components, when mounted horizontal to the board stace, should be approximately centered between the mounting holes. The entire length of the component body should be in contact with the board surface. The maximum space between the component body and the board shall not exceed 0.7 mm [0.03 in]. Components that are required to be mounted off the board shall be elevated at least 1.5 mm [0.06 in]. Components mounted in unsupported holes and required to be elevated shall be provided with lead forms at the board surface, or other mechanical support. For axial leaded components, at least one component lead shall have stress relief provided the component is not clip or adhesive mounted, or other wise constrained, see J-STD-001H Figure 6-1. All axial leads shall have stress relief when the component clipped or adhesive mounted or otherwise constrained.	
	Axial leaded components mounted vertically in unsupported holes shall be mounted with lead forms or other mechanical support.	
	Axial lead components mounted vertically in supported holes shall have component height in accordance with the design. Component clearance (C) from the land to the body or weld bead shall meet the requirements of J-STD-001H Table 6-1.	
	Clearance of radial leaded components that are mounted freestanding, e.g., supported by leads only, shall be between 0.3 mm [0.01 in] and 2 mm [0.08 in]. The spacing between the component and printed board shall not violate minimum electrical clearance.	
	When spacers are used with radial leaded components, the mounting shall meet the requirements of J-STD-001H Table 6-2.	

J-STD-001H Reference	Space and Military Applications Requirements (as changed by this Addendum)		
6.1.1	Lead Forming Part and component leads should be preformed to the final configuration excluding the final clir or retention bend before assembly or installation. The lead forming process shall not damage lead seals, well or connections internal to components, see 4.7.2 Lead Deformation Limits in this Addendum. Leads shall not reformed except for minor adjustments to bend angles.		
	Leads shall extend at least one lead diameter or thickneweld before the start of the bend radius, see J-STD-001		
	Note: Measurement is made from the end of the part. solder seal, solder or weld bead, or any other extension.		
	The lead bend radius shall be in accordance with Table	6-3 of this Addendum.	
	Table 6-3 Lead	Bend Radius	
	Lead Diameter or Thickness	Minimum Bend Radius (R)	
	Less than 0.8 mm [0.03 in]	1 diameter or thickness	
	0.8 to 1.2 mm [0.03 to 0.05 in]	1.5 diameters or thickness	
	Greater than 1.2 mm [0.05 in]	2 diameters or thickness	
6.1.2	Termination Requirements Component leads may be terminated using a straight through, partially clinched, or clinched configuration. The clinch should be sufficient to provide mechanical restraint during the soldering process. The orientation of the clinch relative to any conductor is optional. DIP leads should have at least two diagonally opposing leads partially bent outward. If a lead or wire is clinched, the lead shall be wetted in the clinched area. The outline of the lead should be discernible in the solder connection. Tempered leads shall not be terminated with a full-clinched configuration. Lead protrusion shall not violate minimum electrical clearance requirements. Lead protrusion shall be in accordance with Table 6-4 of this Addendum for supported holes or Table 6-5 of this Addendum for unsupported holes. The presence of a lead shall be verified prior to soldering, see Table 6-4 Note 1 of this Addendum.		
	Table 6-4 Protrusion of I		
	(L) min.	End is discernible in solder, Note 1	
	(L) max.	2.25 mm [0.09 in]	
	Note 1. For components having pre-established lead lengths that are less than board thickness, and the components or lead shoulders are flush to the board surface, the lead end is not required to be visible in the subsequent solder connection.		
	Table 6-5 Protrusion of Leads in Unsupported Holes		
	(L) min.	Sufficient to clinch, or 0.75 mm [0.03 in] for straight through terminations	
	(L) max., Note 1 - clinched	Note 2	
	(L) max., Note 1 - partial clinch or straight through	2.25 mm [0.09 in], Note 2	
	Note 1. Lead protrusion should not exceed 2.5 mm [0.1 in] if there is a soldered connections due to lead deflection or penetration of s environments. Note 2. No danger of shorts.	possibility of violation of minimum electrical spacing, damage to tatic protective packaging during subsequent handling or operating	
	Connector leads, relay leads, tempered leads and leads the maximum length requirement provided that they do	greater than 1.3 mm [0.05 in] diameter are exempt from not violate minimum electrical clearance.	

J-STD-001H Reference	Space and Military Applications Requirements (as changed by this Addendum)			
6.2.2	Through-Hole Component Lead Soldering When soldering component leads into PTH conr of the process is to accomplish 100% fill of the PTH with solder and good wetting to the lands top and bottom. The solder connection shall meet the requirements of Table 6-6 of this Adder of the soldering process, e.g., hand soldering, wave soldering, intrusive soldering, etc.	, lead, and barr		
	Table 6-6 Supported Holes with Component Leads, Minimum Acceptable Condit	ions¹		
	A. Vertical fill of solder. Note 2 and Figure 6-4 of J-STD-001H.	75%		
	B. Circumferential wetting of lead and barrel on solder destination side.	360°		
	C. Percentage of land area covered with wetted solder on solder destination side.	0%		
	D. Circumferential fillet and wetting of lead and barrel on solder source side.	360°		
	E. Percentage of land area covered with wetted solder on solder source side.	75%		
	Note 1. Wetted solder refers to solder applied by any solder process including intrusive soldering. For intrusive soldering, external fillet between the lead and the land.	here may not be a		
	Note 2. The 25% unfilled height includes the sum of both source and destination side depressions.			
6.3.1	Lead Termination Requirements for Unsupported Holes Lead protrusion for unsuppo meet the requirements of Table 6-5 of this Addendum. Solder shall meet the requirements of Addendum. Table 6-7 Unsupported Holes with Component Leads, Minimum Acceptable Conditional Conditions of Component Leads, Minimum Acceptable Conditions of Conditions of Component Leads, Minimum Acceptable Conditions of	Table 6-7 of the		
	A. Circumferential wetting and fillet lead to land	360°		
	B. Percentage of land area covered with wetted solder	75%		
	Note 1. Wetted solder refers to solder applied by the solder process. Note 2. Criteria A and B apply to double-sided boards with a soldered land on one side only.	7 0 70		
7.0	Surface Mounting of Components			
7.0	Designs with via in land may preclude meeting fillet criteria. If this condition exists, solder acceptable defined between the User and the Manufacturer.	nce criteria sh a		
	Solder should not extend under the body of surface mount components whose leads are main similar iron (Fe)-based alloys.	de of Alloy 42		
	Note: The technical data sheets for high density termination and area-array-devices, e.g. Qf unique pre-design, processing and inspection requirements. These should be observed in orde free function.			
7.1.2	Forming Leads shall be formed in such a manner that the lead-to-body seal is not damaged J-STD-001H Figure 7-1. When lead forming is required during the assembly process, leads shal that there is an available minimum lead length for contact to the solder pad as shown in Table 7 dum, see J-STD-001H Figure 7-2.	I be formed su		
	The leads of surface mounted components shall be formed to their final configuration prior to soldering.			
	Note: Where severe loading conditions exist such as Coefficient of Thermal Expansion (CTE) mismatches of severe operational environments, extra consideration should be given to the minimum available contact length.			
	Table 7-1 SMT Lead Forming Minimum Lead Length			
	A. Two lead widths for flat leads.			
	B. Two lead widths for coined leads.			
	C. Two lead diameters for round leads.			
7.1.3	Unintentional Bending There shall be no unintentional lead deformation beyond the limits define Deformation Limits of this Addendum.	ned in 4.7.2 Le		

J-STD-001HS Table 1 Space and Military Applications Requirements (cont.)

Reference Space and Military Applications Requirements (as changed by this Addendum) 7.5.5 Cylindrical End Cap Terminations This component is sometimes referred to as MELF (metal electrode leadless face). Solder connections to components having cylindrical end cap terminations shall meet the dimensional and solder fillet requirements of Tables 7-5 and 7-5A, see Figures 7-5 and 7-5A of this Addendum.

Table 7-5 Dimensional Criteria – Cylindrical End Cap Terminations

Feature	Dim.	Requirement
Maximum Side Overhang	А	25% (W) or 25% (P), whichever is less, Note 1
End Overhang	В	Not permitted
Minimum End Joint Width, Note 2	С	50% (W) or 50% (P), whichever is less
Minimum Side Joint Length	D	75% (R) or 75% (S), whichever is less, Note 6
Maximum Fillet Height	E	Note 5
Minimum Fillet Height (end and side)	F	(G) + 25% (W) or (G) + 1.0 mm [0.04 in], whichever is less
Solder Thickness	G	Note 4
Minimum End Overlap	J	75% (R), Note 6
Land Width	Р	Note 3
Termination Length	R	Note 3
Land Length	S	Note 3
Termination Diameter	W	Note 3

- Note 1. Does not violate minimum electrical clearance.
- Note 2. (C) is inspected at the narrowest point of the required fillet.
- Note 3. Unspecified parameter or variable in size as determined by design.
- Note 4. Wetting is evident.

J-STD-001H

- Note 5. The maximum fillet may overhang the land or extend onto the top metallization but does not touch the top of the component. Solder may touch the bottom half of the component body.
- Note 6. Does not apply to components with end-only terminations.

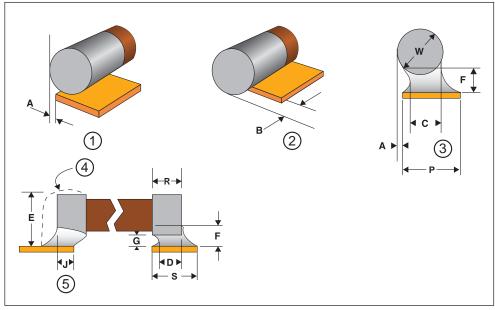


Figure 7-5 Cylindrical End Cap Terminations

- 1. Side overhang
- 2. End overhang
- 3. End joint width
- 4. See Note 5, Table 7-5
- 5. Side joint length and end overlap

Reference 7.5.5	Space and Military Applications Requirements (as changed by this Addendum)			
(cont.)	Table 7-5A Dimensional Criteria – Center Termination (When Present) – Cylindrical End Cap Terminations			
	Feature	Dim.	Requirement	
	Maximum Side Overhang	А	25% (Cw) or 25% (Cp), whichever is less	
	Minimum Side Joint Length, Note 2	D	75% (Cw) or 75% (Cp), whichever is less	
	Maximum Fillet Height	E	Note 5	
	Minimum Fillet Height	F	Note 4	
	Solder Thickness	G	Note 4	
	Termination Width	Cw	Note 3	
	Termination Height	Ch	Note 3	
	Land Width	Ср	Note 3	
	Note 2. (C) is inspected at the narrowest point of the required fillet. Note 3. Unspecified parameter or variable in size as determined by design. Note 4. Wetting is evident. Note 5. The maximum fillet may overhang the land or extend onto the top metallization but does not touch the top of the component. Solder may touch the bottom half of the component body.			

J-STD-001HS Table 1 Space and Military Applications Requirements (cont.)

Reference Space and Military Applications Requirements (as changed by this Addendum) 7.5.6 Castellated Terminations If parts with castellated terminations are chosen by design, their use shall be approved by the User. Connections formed to castellated terminations shall meet the dimensional and solder fillet requirements of Table 7-6 of this Addendum, see Figure 7-6 of J-STD-001H.

Table 7-6 Dimensional Criteria – Castellated Terminations

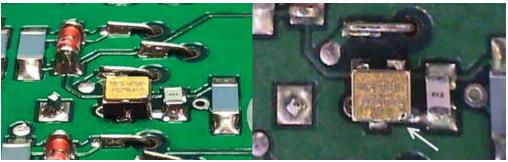
Table 7 0 Difficiliation	Gusteriated Terrimianoris	
Feature	Dim.	Requirement
Maximum Side Overhang	А	25% (W), Note 1
End Overhang	В	Not permitted
Minimum End Joint Width	С	75% (W), Note 5
Minimum Side Joint Length	D	Depth of castellation
Maximum Fillet Height	E	Notes 1, 4
Minimum Fillet Height	F	(G) + 50% (H)
Solder Thickness	G	Note 3
Castellation Height	Н	Note 2
Land Length	S	Note 2
Castellation Width	W	Note 2

- Note 1. Does not violate minimum electrical clearance.
- Note 2. Unspecified parameter or variable in size as determined by design.
- Note 3. Wetting is evident.

J-STD-001H

Note 4. The maximum fillet may extend past the top of the castellation provided it does not contact the body. For castellations that extend to the component lid, solder may extend beyond the top of the castellation and make contact with the component body, including the braze seal, and extend to the top of and wet the metallic lid. See J-STD-001HS Figure 7-1. If solder is present on the lid or its seal, no effort should be made to remove it.

Note 5. (C) is measured at the narrowest point of the required fillet.



J-STD-001HS Figure 7-1

J-STD-001HS Table 1 Space and Military Applications Requirements (cont.)

J-STD-001H Reference Space and Military Applications Requirements (as changed by this Addendum) 7.5.7 Flat Gull Wing Leads Connections formed to flat gull wing shaped leads shall meet the dimensional and solder fillet requirements of Table 7-7, see Figure 7-7 of this Addendum.

Toe down is the formed condition of the foot where the heel and the toe are not planar to the board, with the toe biased downward. The angle can be from a few degrees up to 45 degrees, see Figure 7-7 of this Addendum. Angles over 45 degrees are considered butt/I leads, see 7.3 Parts Configured for Butt/I Lead Mounting.

Table 7-7 Dimensional Criteria - Flat Gull Wing Leads

Feature		Requirement					
Maximum Side Overhang	А	25% (W) or 0.5 mm [0.02 in], whichever is less, Note 1					
Maximum Toe Overhang	В	Not permitted when (L) is less than 2 (W), Note 1					
Minimum End Joint Width	С	75% (W), Note 6					
Minimum Side Joint Length	D	100% of available lead to land interface or 2 (W), whichever is less, Note 7					
Maximum Heel Fillet Height	Е	Note 4					
Minimum Heel Fillet Height	F	(G) + (T), Note 5					
Solder Thickness	G	Note 3					
Formed Foot Length	L	Note 2					
Lead Thickness	Т	Note 2					
Lead Width	W	Note 2					

- Note 1. Does not violate minimum electrical clearance.
- Note 2. Unspecified parameter or variable in size as determined by design. When lead forming is required, see 7.1.2 Forming of this Addendum
- Note 3. Wetting is evident.
- Note 4. Solder does not touch package body or end seal, see J-STD-001H 7.1.1 Plastic Components for exceptions.
- Note 5. In the case of a toe-down lead configuration, the Minimum Heel Fillet Height (F) extends at least to the mid-point of the outside lead bend.
- Note 6. (C) is inspected at the narrowest point of the required fillet.
- Note 7. If Side Overhang (A) is present, then the Side Joint Length (D) on the overhanging portion of the lead may not be inspectable.

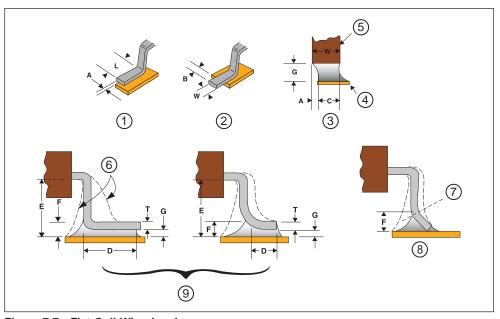


Figure 7-7 Flat Gull Wing Leads

- 1. Side overhang
- 2. Toe overhang
- 3. End joint width
- 4. Land
- 5. Lead

- 6. Solder fillet may extend through the top bend.
- 7. Line bisecting lower bend
- 8. Toe down heel fillet height
- 9. Side joint length

J-STD-001H Reference	Space and Military Applications Requirements (as changed by this Addendum)							
7.5.8	Round or Flattened (Coined) Gull Wing Leads Connections formed to round or flattened (coined) leads shall meet the dimensional and fillet requirements of Table 7-8 of this Addendum and J-STD-001H Figure 7-8.							
	Table 7-8 Dimensional Criteria – Round or Flattened (Coined) Gull Wing Leads							
	Feature	Dim.	Requirement					
	Maximum Side Overhang		25% (W) or 0.5 mm [0.02 in], whichever is less, Note 1					
	Maximum Toe Overhang	В	Not permitted when (L) is less than 2 (W), Note 1					
	Minimum End Joint Width	С	75% (W)					
	Minimum Side Joint Length	D	100% of available lead to land interface, Note 6					
	Maximum Heel Fillet Height	Е	Note 4					
	Minimum Heel Fillet Height	F	(G) +(T), Note 5					
	Solder Thickness	G	Note 3					
	Formed Foot Length	L	Note 2					
	Minimum Side Joint Height	Q	(G) + 50% (T), Note 6					
	Thickness of Lead at Joint Side	Т	Note 2					
	Flattened Lead Width or Diameter of Round Lead	W	Note 2					
	Note 4. Solder fillet may extend through the top bend. Solder does not touch package body or end seal, see J-STD-001H 7.1.1 Plastic Components for exceptions. Note 5. In the case of a toe-down lead configuration, the Minimum Heel Fillet Height (F) extends at least to the mid-point of the outside lead bend. Note 6. A Side Fillet (and corresponding Dimensions (D) & (Q)) may not be visually inspectable on a side where acceptable Side Overhang (A) is present.							
7.5.14	Surface Mount Area Array Packages Process de assembly methods and implementation of materials. process is established to determine compliance for example.	The are	ent and control is essential for continued success of a array criteria defined herein assumes an inspection Ray or visual inspection processes.					
	Visual inspection:							
	When visual inspection is the method used to verifing from J-STD-001H 1.12.2.2 applies.	y produ	ct acceptance, the appropriate magnification table(s)					
	The state of the s		he area array component shall be visually inspected.					
	The area array component should align in both X (if present).	& Y dire	ections with the corner markers on the printed board					
	Absence of leads, e.g., solder ball or columns, are c	lefects u	unless specified by design.					
	Evaluation of X-Ray images shall be used to allow as normal visual means.	ssessme	ent of characteristics that cannot be accomplished by					
	Note: See 1.11 Acceptance Requirements of this X-Ray.	Addend	dum for NDE User concurrence prior to the use of					
	Process validation and control may be used in lieu of X-Ray/visual inspection provided objective evidence is approved by the User prior to use.							
	Note: X-Ray equipment not intended for electronic assemblies or not properly set up can damage sensitive components.							
	Area array process guidance is provided in IPC-7095, which contains recommendations developed from extensive discussion of process development issues.							
	Surface mount area array packages shall meet the dimensional and solder fillet requirements of J-STD-001H Table 7-15 for components with collapsing balls, J-STD-001H Table 7-16 for components with noncollapsing balls, and J-STD-001H Table 7-17 for column grid arrays.							
			shall be agreed upon between the Manufacturer and					

J-STD-001HS Table 1 Space and Military Applications Requirements (cont.)

J-STD-001H Reference Space and Military Applications Requirements (as changed by this Addendum) 7.5.15 Bottom Termination Components (BTC) These criteria are also applicable to Small Outline Integrated Circuit No Leads (SOICNL). Criteria for nonvisible part of thermal plane solder connections (including voids) are not described in this document and shall be established by agreement between the Manufacturer and the User. The thermal transfer plane acceptance criteria are design and process related. Issues to consider include, but are not limited to, the component supplier's application notes, solder coverage, voids, solder height, maximum junction temperature, etc. When soldering these types of components, voiding in the thermal plane is common. Solder, when required, shall meet documented requirements. Connections formed to components having no significant external lead form shall meet the dimensional and solder fillet requirements of Table 7-18 of this Addendum and J-STD-001H Figure 7-16. There are some package configurations that have no toe exposed or do not have a continuous solderable surface on the exposed toe on the exterior of the package. A toe fillet will not form. Bottom Termination Component (BTC) process guidance is provided in IPC-7093, which contains recommendations developed from extensive discussion of BTC process development issues. Process development and control is essential for continued success of assembly methods and implementation of materials. Evaluation of X-Ray images shall be used to allow assessment of characteristics that cannot be accomplished by normal visual means, e.g., when criteria for voids and thermal plane solder coverage are established. Note: See 1.11 Acceptance Requirements of this Addendum for NDE User concurrence prior to the use of X-Ray. Thermal plane voids shall comply with criteria established between the Manufacturer and User. Table 7-18 Dimensional Criteria - BTC Feature Dim Requirement Maximum Side Overhang 25% (W), Note 1 Α В Toe Overhang (outside edge of component termination) Not permitted Minimum End Joint Width С 75% (W) Note 6 Minimum Side Joint Length D Note 4 F Minimum Toe (End) Fillet Height Notes 2, 5 Solder Thickness G Note 3 Н Termination Height Note 5 Ρ Note 2 Land Width Termination Width W Note 2 Note 1. Does not violate minimum electrical clearance. Note 2. Unspecified parameter or variable in size as determined by design. Note 3. Wetting is evident. Note 4. Not a visually inspectable attribute. See 4.15.3 of this Addendum.

Note 5. (H) = height of solderable surface of lead, if present. Some package configurations do not have a continuous solderable surface on the

sides and do not require a toe (end) fillet. **Note 6.** (C) is measured at the narrowest point of the required fillet.

	J-51D-001H5 Table 1 Space and Military	, дррпс	ations requirements (somi)					
J-STD-001H Reference	Space and Military Applications Requirements (as changed by this Addendum)							
7.5.16	Components with Bottom Thermal Plane Terminations (D-Pak) Criteria for nonvisible parts of thermal plane solder connections are not described in this document and shall be established between the Manufacturer and the User. The thermal transfer plane acceptance criteria are design and process related. Issues to consider include, but are not limited to, component supplier's application notes, solder coverage, voids, solder height, etc. When soldering these types of components, voiding in the thermal plane is common.							
	Evaluation of X-Ray images shall be used to allow assessment of characteristics that cannot be accomplished by normal visual means. Note: See 1.11 Acceptance Requirements of this Addendum for NDE User concurrence prior to the use of X-Ray.							
	The mounting and solder requirements for SMT term tion being used.	ninations	s shall meet the criteria for the type of lead termina-					
	Connections formed to components with bottom the meet the dimensional and solder fillet requirements of		ne terminations, see J-STD-001H Figure 7-17, shall 7-19 of this Addendum.					
	Table 7-19 Dimensional Criteri	ia - Botte	om Thermal Plane Terminations					
	Feature (all connections except thermal plane)	Dim.	Requirement					
	Maximum Side Overhang	А						
	Toe Overhang	В						
	Minimum End Joint Width, Note 4							
	Minimum Side Joint Length	D	Criteria for the type of lead					
	Maximum Heel Fillet Height	Е	termination being used.					
	Minimum Heel Fillet Height F							
	Solder Thickness G							
	Lead Thickness							
	Feature (only for the thermal plane connection)		Requirement					
	Thermal Plane Side Overhang		Not greater than 25% of termination width					
	Thermal Plane End Overhang		No overhang					
	Thermal Plane Minimum End Joint Width, Note 2		100% wetting to land in the end-joint contact area					
	Thermal Plane Side Joint Length	D	Note 1					
	Thermal Plane Solder Fillet Thickness	G	Wetting is evident when a fillet is present					
	Thermal Plane Voids		Note 1					
	Thermal Plane Termination Width	W	Note 3					
	Thermal Plane Land Width P Note 3							
	Note 1. As established between the Manufacturer and User. Note 2. Solder wetting is not required on trimmed edges of a thermal plane that expose non-wettable vertical surfaces. Note 3. Unspecified parameter or variable in size, as determined by design. Note 4. (C) is measured at the narrowest point of the required fillet.							
7.5.17	Flattened Post Terminations If parts with flattene ing acceptance criteria, shall be approved by the U		rerminations are chosen by design, their use, includ-					

-STD-001H Reference	Space and Military Applications Requirements (as changed by this Addendum)					
7.5.19	Vertical Cylindrical Cans with Outward L-Shaped Lead Terminations The vertical cylindrical cans with outward L-shaped lead termination criteria defined herein assumes an inspection process is established to determine compliance for either x-ray or normal visual inspection processes. To a limited extent, this may involve visual assessment, but more commonly requires evaluation of x-ray images to allow assessment of characteristics that cannot be accomplished by normal visual means. If Vertical Cylindrical Cans with Outward L-Shaped Leads Terminations are chosen by design, acceptance criteria shall be approved by the User prior to use.					
	Visual inspection requirements:					
	and 1-4 apply.		eptance the magnification levels of Tables 1 quirements of Table 7-22 of this Addendum			
	Process development and control is essen in lieu of x-ray/visual inspection provided o	tial for continued success bjective evidence of com	s. Process validation and control can be use pliance is available.			
	Note: X-ray equipment not intended for electronic assemblies or not properly set up can damage sensitive ponents. See Appendix D.					
	1'					
	Connections formed to vertical cylindrical sional and solder fillet requirements of Tabl style is typically found on aluminum electrons.	e 7-22, see Figures 7-20 Olytic capacitors, or two-p	ped lead terminations shall meet the dime and 7-21 of this Addendum. This termination oin SMT Crystal Oscillators. th Outward L-Shaped Lead Terminations			
	Connections formed to vertical cylindrical sional and solder fillet requirements of Tabl style is typically found on aluminum electrons.	e 7-22, see Figures 7-20 Olytic capacitors, or two-p	and 7-21 of this Addendum. This termination SMT Crystal Oscillators.			
	Connections formed to vertical cylindrical sional and solder fillet requirements of Table style is typically found on aluminum electromagnetic Table 7-22 Dimensional Criteria – Vertical Connections of the Connection of Connections of Table 7-22 Dimensional Criteria – Vertical Connections of	e 7-22, see Figures 7-20 olytic capacitors, or two-p tical Cylindrical Cans wi	and 7-21 of this Addendum. This termination SMT Crystal Oscillators. th Outward L-Shaped Lead Terminations			
	Connections formed to vertical cylindrical sional and solder fillet requirements of Tabl style is typically found on aluminum electro Table 7-22 Dimensional Criteria – Vertical Section (Connection) (e 7-22, see Figures 7-20 olytic capacitors, or two-p tical Cylindrical Cans wi Dim.	and 7-21 of this Addendum. This termination SMT Crystal Oscillators. th Outward L-Shaped Lead Terminations Requirement			
	Connections formed to vertical cylindrical sional and solder fillet requirements of Tabl style is typically found on aluminum electro Table 7-22 Dimensional Criteria – Vertical Feature Maximum Side Overhang	e 7-22, see Figures 7-20 olytic capacitors, or two-p tical Cylindrical Cans wi Dim. A	and 7-21 of this Addendum. This termination SMT Crystal Oscillators. th Outward L-Shaped Lead Terminations Requirement 25% (W), Note 1			
	Connections formed to vertical cylindrical sional and solder fillet requirements of Table style is typically found on aluminum electrons. Table 7-22 Dimensional Criteria – Vertical Feature Maximum Side Overhang Maximum Toe Overhang	e 7-22, see Figures 7-20 plytic capacitors, or two-p tical Cylindrical Cans wi Dim. A B	and 7-21 of this Addendum. This termination SMT Crystal Oscillators. th Outward L-Shaped Lead Terminations Requirement 25% (W), Note 1 Not permitted			
	Connections formed to vertical cylindrical sional and solder fillet requirements of Tabl style is typically found on aluminum electromage Table 7-22 Dimensional Criteria – Vertomage Maximum Side Overhange Maximum Toe Overhange Minimum End Joint Width	e 7-22, see Figures 7-20 olytic capacitors, or two-p tical Cylindrical Cans wi Dim. A B C	and 7-21 of this Addendum. This termination SMT Crystal Oscillators. th Outward L-Shaped Lead Terminations Requirement 25% (W), Note 1 Not permitted 75% (W)			
	Connections formed to vertical cylindrical sional and solder fillet requirements of Table style is typically found on aluminum electronal trace of Table 7-22 Dimensional Criteria – Vertical Criteria – Vertical Table 7-22 Dimensional Criteria – Vertical Criteria – Vertical Table 7-22 Dimensional Criteria – Vertical Cri	e 7-22, see Figures 7-20 olytic capacitors, or two-p tical Cylindrical Cans wi Dim. A B C D	and 7-21 of this Addendum. This termination SMT Crystal Oscillators. th Outward L-Shaped Lead Terminations Requirement 25% (W), Note 1 Not permitted 75% (W) 100% (L)			
	Connections formed to vertical cylindrical sional and solder fillet requirements of Tabl style is typically found on aluminum electrons Table 7-22 Dimensional Criteria – Vertical Feature Maximum Side Overhang Maximum Toe Overhang Minimum End Joint Width Minimum Side Joint Length Maximum Heel Fillet Height	e 7-22, see Figures 7-20 plytic capacitors, or two-p tical Cylindrical Cans wi Dim. A B C D E	and 7-21 of this Addendum. This termination SMT Crystal Oscillators. th Outward L-Shaped Lead Terminations Requirement 25% (W), Note 1 Not permitted 75% (W) 100% (L) Note 4			
	Connections formed to vertical cylindrical sional and solder fillet requirements of Tabl style is typically found on aluminum electrons Table 7-22 Dimensional Criteria – Verton Feature Maximum Side Overhang Maximum Toe Overhang Minimum End Joint Width Minimum Side Joint Length Maximum Heel Fillet Height	e 7-22, see Figures 7-20 plytic capacitors, or two-p tical Cylindrical Cans wi Dim. A B C D E F	and 7-21 of this Addendum. This termination SMT Crystal Oscillators. th Outward L-Shaped Lead Terminations Requirement 25% (W), Note 1 Not permitted 75% (W) 100% (L) Note 4 (G) + (T)			
	Connections formed to vertical cylindrical sional and solder fillet requirements of Table style is typically found on aluminum electrons Table 7-22 Dimensional Criteria – Vertical Feature Maximum Side Overhang Maximum Toe Overhang Minimum End Joint Width Minimum Side Joint Length Maximum Heel Fillet Height Solder Thickness	e 7-22, see Figures 7-20 plytic capacitors, or two-p tical Cylindrical Cans wi Dim. A B C D E F G	and 7-21 of this Addendum. This termination SMT Crystal Oscillators. th Outward L-Shaped Lead Terminations Requirement 25% (W), Note 1 Not permitted 75% (W) 100% (L) Note 4 (G) + (T) Note 3			
	Connections formed to vertical cylindrical sional and solder fillet requirements of Tabl style is typically found on aluminum electrotable 7-22 Dimensional Criteria – Verto Feature Maximum Side Overhang Maximum Toe Overhang Minimum End Joint Width Minimum Side Joint Length Maximum Heel Fillet Height Minimum Heel Fillet Height Solder Thickness Formed Foot Length	e 7-22, see Figures 7-20 plytic capacitors, or two-p tical Cylindrical Cans wi Dim. A B C D E F G L	and 7-21 of this Addendum. This termination SMT Crystal Oscillators. th Outward L-Shaped Lead Terminations Requirement 25% (W), Note 1 Not permitted 75% (W) 100% (L) Note 4 (G) + (T) Note 3 Note 2			
	Connections formed to vertical cylindrical sional and solder fillet requirements of Tabl style is typically found on aluminum electrons Table 7-22 Dimensional Criteria – Vertical Feature Maximum Side Overhang Maximum Toe Overhang Minimum End Joint Width Minimum Side Joint Length Maximum Heel Fillet Height Solder Thickness Formed Foot Length Land Width	e 7-22, see Figures 7-20 plytic capacitors, or two-p tical Cylindrical Cans wi Dim. A B C D E F G L	and 7-21 of this Addendum. This termination SMT Crystal Oscillators. th Outward L-Shaped Lead Terminations Requirement 25% (W), Note 1 Not permitted 75% (W) 100% (L) Note 4 (G) + (T) Note 3 Note 2 Note 2			

Note 4. Solder does not touch package body or end seal, except for the plastic terminal platform/base.

J-STD-001HS Table 1 Space and Military Applications Requirements (cont.)

J-STD-001H Reference Space and Military Applications Requirements (as changed by this Addendum) 7.5.19 (cont.) Figure 7-20 Examples of Vertical Cylindrical Cans with Outward L-Shaped Lead Terminations A. Standard Aluminum Electrolytic Capacitors B. Vibration Resistant (Ruggedized) Aluminum Electrolytic Capacitors C. SMT Two-Pin Oscillators Vertical Cylindrical Cans with Outward L-Shaped Lead Terminations

J-STD-001HS Table 1 Space and Military Applications Requirements (cont.)

Reference	Space and Military Applications Requirements (as changed by this Addendum)
7.5.20	Wrapped Terminals Connections formed to wrapped terminals (terminals made by a wire going around a sup-
	porting element/wrap that is then metallized) shall meet the dimensional requirements of Table 7-23, see Figures
	7-22, 7-23, 7-24 and 7-25 of this Addendum.

Table 7-23 Dimensional Criteria – Wrapped Terminals

Feature	Dim.	Requirement
Maximum Side Overhang	А	25% (W), Note 1
End Overhang	В	Not permitted
Minimum End Joint Width	С	150% (R), Note 5
Minimum Side Joint Length	D	75% (R)
Maximum Heel Fillet Height	E	Note 6
Minimum Heel Fillet Height	F	(G) + (T), Note 4
Solder Thickness	G	Note 3
Lead Thickness	Т	Note 2
Termination Length	R	Note 2
Termination Diameter	W	Note 2

- Note 1. Does not violate minimum electrical clearance.
- Note 2. Unspecified dimension or variable in size as determined by design.
- Note 3. Wetting is evident.

J-STD-001H

- Note 4. (F) is inspected at the lowest point of the required fillet, see Figure 7-25.
- Note 5. (C) is inspected at the narrowest point of the required fillet.
- Note 6. Solder may contact the component body.



Figure 7-22 Wrapped Terminal – SMT Inductor – Bottom View



Figure 7-23 Wrapped Terminal – SMT Inductor – Top View

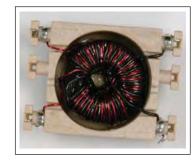


Figure 7-24 Wrapped Terminal – SMT Component

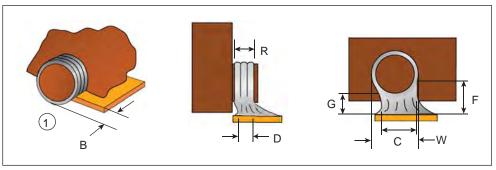


Figure 7-25 Wrapped Terminals

J-STD-001H Reference		Space and Military Applications Requirements (as changed by this Addendum)					
8.0	of the r	Cleaning and Residue Requirements Unless otherwise specified by design, or by the User, the acceptability of the residue condition shall be determined at the point of manufacturing process for each assembly just prior to the application of conformal coating, or on the final assembly if conformal coating is not applied.					
8.1	Qualified Manufacturing Process Unless otherwise specified by the User, the Manufacturer shall quali soldering and/or cleaning processes that result in acceptable levels of flux and other residues. Objective evidence shall be available for review. See J-STD-001H Appendix C for examples of objective evidence. Rework processes shall be included in the process qualification.						
		e of the 1.56 µg/NaCl equivalence/cm2 value for resistivity of solvent extract (ROSE), with no other sup-objective evidence, is not considered an acceptable basis for qualifying a manufacturing process, see P-019.					
8.1.1	a clean The cle required	ng Designator Unless otherwise specified by the User/Design Authority, the Manufacturer should specify ing designator that establishes the cleaning option and process control tests for manufacturing residues. Eaning designator is a 2-digit (minimum) code that describes the cleaning and process control testing d for assemblies under this standard. The code begins with the letter "C" and then a dash followed by two de digits. The first digit represents the cleaning option:					
		Table 8-1 Designation of Surfaces to be Cleaned					
	0	No surfaces to be cleaned					
	1	One side (solder source side) of assembly to be cleaned					
	2	Both sides of assembly to be cleaned					
	The sec	cond and any subsequent digits define the requirements for process control of residues:					
		Table 8-2 Residue Testing for Process Control					
	0	No test required					
	1 Test for rosin residues required, see 8.6 Non-lonic Residues						
	2	Test for ionic residues required, see 8.2 Ionic Process Monitoring					
	3	Test for surface insulation resistance (Note 1)					
	4	Test for surface organic contaminants (Note 1)					
	5	Other testing (Note 1)					
	Note 1.	As agreed between Manufacturer and User if required.					
	A Clear tor of C surface see 8.4	absence of a specified cleaning designator, the designator C-22 shall apply to printed board assemblies. In Designator of C-00 specifies a "no clean" process with no testing for residues. A Cleaning Designator-223 specifies a printed board assembly requiring cleaning on both sides, in addition to ionic residue and insulation resistance (SIR) testing. Cleanliness designator C-10 and the visual requirements for cleanliness, Foreign Object Debris (FOD) and 8.5 Visible Residues of this Addendum, shall apply to designs incorpoliscrete solder terminations, e.g., solder cups, wire splices, or wire/braid, not terminated to a printed board obly.					
8.3.1	Level 1 – Major Changes Requiring Validation When major elements of the qualified processes are char validation of the acceptability of the change(s) shall be performed and documented. Major changes sha approved by the User prior to use, see 3.1 Materials of this Addendum.						
	The foll	owing are considered major elements impacting residue levels.					
	• Flux or flux-bearing materials (e.g., flux, solder paste, paste flux, cored wire solder)						
	Cleaning agents (e.g., solvents, aqueous detergents, topical cleaners)						
	Changes in solder mask type						
	Changes in printed board fabrication processes or surface metallization						
		raphic change in manufacturing location					
8.4	lodged	n Object Debris (FOD) Assemblies shall be free of foreign particles that are loose, e.g., could be disin the service environment of the product or violate minimum electrical clearance.					
	the sys	balls are allowed if proven secured, i.e., will not come loose during transportation, storage, or operation of tem, with a documented specialized process. The specialized process and acceptance criteria shall be ed by the User prior to use. The approved process shall be applied to 100% of all solder balls. Data gen-by the approved process shall be maintained and available for review.					

J-STD-001H Reference	Space and Military Applications Requirements (as changed by this Addendum)
8.5	Visible Residues As an exception to J-STD-001H Table 1-4, surfaces cleaned shall be inspected between 4X and 10X magnification. Assemblies subjected to cleaning processes shall be free of visible residues that violate minimum electrical clearance, unless identified as benign through laboratory analysis or equivalent. All other visible residue requirements shall be as established between Manufacturer and User.
9.1.1	Blistering/Delamination There shall be no blistering or delamination between any of the laminate layers, or between the laminate and the metallization.
	Note: Measling is NOT the same as blistering or delamination. See IPC-T-50 and IPC-A-610 for clarification.
9.1.2	Weave Exposure/Cut Fibers There shall be no non-wetted exposed glass fibers. There shall be no surface damage that cuts into laminate fibers.
	Exposed fibers may extend onto the top and bottom surfaces of the printed board a maximum of 0.6 mm [0.02 in] around the perimeter of the printed board or around unsupported holes without lands.
9.1.9	Burns There shall not be any heat-caused discoloration.
9.1.11	Measles Measles shall not bridge non-common conductors.
10.0	Coating, Encapsulation, Staking and Bonding
	All assemblies shall be cleaned before processing. After cleaning, prior to processing, assemblies shall be handled in a manner that prevents contamination.
	Items exposed to uncured silicone material shall not be used for processing other material. An authorized exception is allowed only in cases where equipment is used for co-curing processes and the Manufacturer has demonstrated through system tests that non-silicone material properties have not changed and design requirements are met. Objective evidence shall be maintained and available for review.
	 a. A mix record shall be created for each mixed batch of multi-part polymers used for conformal coating, encapsulating, staking or bonding. At a minimum, this record shall include the date mixed, supplier's part number and date/lot code, shelf life expiration date (of all parts of the mix), the mix ratio for all constituents used, traceability to the hardware the material is being applied to, test specimen acceptance test results, and material supplier's datasheet acceptance criteria. As an exception, Manufacturers that use continuous run processes shall have a documented process for mixing and traceability. b. For one-part polymers, the supplier's part number and lot/date code, and shelf life expiration date shall be documented.
	 c. Non-porous containers and mixing tools shall be used. Containers and mixing tools shall be selected such that their use in combination cannot introduce contamination into the mix, e.g., a metal stirrer can scrape shavings from a plastic container. d. Fillers, e.g., thickening agents, thermal property enhancers, etc., shall be treated to remove detrimental moisture and other volatiles prior to adding to any polymer. e. After assembly and prior to staking, coating, encapsulating or bonding, the assembly shall be cleaned. f. After final cleaning and prior to coating or encapsulating, the assembly shall be treated to remove detrimental
	 moisture. g. Staking and bonding shall be performed prior to conformal coating. h. Tapes and other maskants with conductive material in the adhesive shall not be used to mask over printed board conductor patterns. i. When coating, encapsulation, or staking materials are applied to through-hole glass, ceramic, or hermetic components, the components shall be protected to prevent cracking unless the material has been selected so as not to damage the components/assembly in its service environment. j. Materials shall be cured in accordance with a documented cure schedule and within the thermal limitations of the hardware. Objective evidence of full cure for each batch of material shall be documented. A witness sample may be used for this verification. k. When fluorescent conformal coating materials are used, coverage and location shall be determined by UV-light examination.
10.1.3	Application Conformal coating may be applied by spray, dip, brush, vacuum deposition, or other application methods, but shall be applied in accordance with a documented procedure. Coating shall be applied only to areas designated for coverage on the assembly drawing/documentation. Assembly drawing/documentation should indicate all areas to be kept free of conformal coating and the tolerance on the keep-out zone.

J-STD-001H Reference	Space and Military Applications Requirements (as changed by this Addendum)
10.1.11	Rework or Touchup Procedures that describe the removal and replacement of conformal coating shall be documented and available for review. Chemical stripping processes shall be approved by the User prior to use.
	The coating rework or touchup areas shall meet the requirements of the assembly drawing(s)/documentation. If thickness measurements are required in the reworked area, the validation process shall be documented and available for review.
	Note: Conformal coating buildup on or around some component types such as glass or ceramic bodied components may cause damage. Coating touch-up should be applied as close to the original coating thickness as possible.
10.3.1.2	Staking - Application - SMT The following criteria apply to surface mount components only.
	a. Components whose largest dimension is their height – The staking material shall be applied to a minimum height of 25% of each individual component's body height. Slight flow of staking material under the component body is acceptable if it does not violate J-STD-001H 10.3.1 Staking – Application.
	For closely spaced arrays, fillet height requirements for the two outer end-faces shall be the same as for an individual component. In addition, the top inner surfaces shall be bonded / staked to each other for at least 50% of the component's width.
	b. Components whose largest dimension is their diameter or length, e.g., QFPs – Rectangular components shall be staked with a bead of staking material placed at each corner of the component. For each bead, the staking material shall contact a minimum 25% of the height of the component body. Slight flow of staking material under the component body is acceptable if it does not violate J-STD-001H 10.3.1 Staking – Application.
10.4 [NEW]	Bonding (Adhesive) The bonding criteria below shall be used when criteria are not provided by the engineering documentation.
	 a. The bonding material shall adhere to all surfaces to be joined. b. Leads of thermistors, platinum resistance thermometers (PRT), and similar components shall be dressed to provide stress relief. For disc-shaped/wafer components, e.g., thermistors, at least one lead shall not be embedded in the bonding material. See the staking requirements in 5.6.3 of this Addendum when components have leads longer than 2.5 cm [1 in] or are connected by wires. c. Squeeze-out shall be visible unless sheet adhesive is used. Squeeze-out shall not negate stress relief of the component and shall not preclude the component from meeting other requirements in the standard.
	Note: These criteria are not intended for bonding used for thermal transfer; refer to engineering documentation.
12.2	Repair Repair is the act of restoring the functional capability of a defective article in a manner that does not assure compliance of the article with applicable drawings or specifications. A hardware defect shall not be repaired until the discrepancy has been documented and only after authorization from the User for each incident. The repair method shall be determined by agreement between the Manufacturer and the User.



Standard Improvement Form

The purpose of this form is to provide the Technical Committee of IPC with input from the industry regarding usage of the subject standard.

Individuals or companies are invited to submit comments to IPC. All comments will be collected and dispersed to the appropriate committee(s).

IPC J-STD-001HS

If you can provide input, please complete this form and return to:

IPC

3000 Lakeside Drive, Suite 105N Bannockburn, IL 60015-1249

Fax: 847 615.7105 E-mail: answers@ipc.org www.ipc.org/standards-comment

1. I recommend changes to the following:	
Requirement, paragraph number	
Test Method number, paragraph number	
The referenced paragraph number has proven to be:	
Unclear Too Rigid In Error	
Other	
2. Recommendations for correction:	
3. Other suggestions for document improvement:	
Submitted by:	
Name	Telephone
Company	E-mail
*** V	
Address	
City/State/Zip	Date







Application for Membership

Quality. Reliability. Consistency. IPC.

www.ipc.org/membership

Thank you for your decision to join IPC.

The following contact information is for renewal purposes. To manage your email preferences, please visit www.ipc.org/opt-in.

Company Name (List all compa	ny, parent company or division	n names used in i	the last live year	rs. Please include any me	rger or a	cquisiuon name changes so t	we can update our record
*Company Website			*Phone			*Email	
*Global Revenue\$			*Nu	ımber of Employees	Corpo	rate-wide	
*Street Address							
*Country	*City	*State			*Zip	*Zip Code	
*Contact	*First/Given Name	*Last/Surr	name	*Title		*E-mail	*Phone
Primary Contact Billing Contact							
Free IPC Standard Recipient							
Government Relations Contact							
Training Contact							
Quality Control/Operations Lead Contact							
o best serve your specific	_						
Primary Company Category (check one)	Secondary Company (check all that apply)	Categories	For Suppl	iers only (check all that a	ipply)	Industries you serv	(e (check all that apply)
PCB	PCB EMS ODM OEM Wire Harness Mfr Design Services Software Developer Consulting Group Supplier Other		PCB EMS ODM OEM Wire Harne What do y Capital Equation Components Materials Chemicals Power elect Software	uipment s and connectors etronics als (enclosures, etc.) rvices the future	00000 000000 0000	Aerospace Automotive/Transportatic Communications Infrast Consumer Technolog Defense/Military Energy/Industrial E-Textiles Medical/Instrument Recreational (RV, Marin Semiconductors Off-Highway Other	tructureEquipment y C





WHMA- Application for Membership

Membership Dues

Membership will begin on the 1st of the month closest to when the application and dues payment are received, and will continue for one year, two years (savings of 10%), or three years (savings of 15%) based on the choice indicated below.* All fees are quoted in U.S. dollars. NEW! Receive 50% off your first year for first time members! Past membership will be verified upon receipt of your application.

Company Annual Revenue							
Annual Revenue	Annual Revenue 1 Year Membership 2 Year Membership (10% discount)				3 Year Membership (15% discount)		
<\$1M		\$550		\$495 per year		\$468 per year	
\$1M - <\$5M		\$850		\$765 per year		\$722 per year	
\$5M - <\$25M	\$	1,450		\$1,305 per year		\$1,233 per year	
\$25M - <\$50M	\$	1,700		\$1,530 per year		\$1,445 per year	
\$50M - <\$100M	\$	2,050		\$1,845 per year		\$1,743 per year	
\$100M - <\$250M	\$	2,400		\$2,160 per year		\$2,040 per year	
\$250M - <\$500M	\$	3,000		\$2,700 per year		\$2,550 per year	
\$500M - <\$1B	\$	3,500		\$3,150 per year		\$2,975 per year	
\$1B - <\$2.5B	\$	4,000		\$3,600 per year		\$3,400 per year	
\$2.5B+	\$	4,600		\$4,140 per year		\$3,910 per year	
Education Institution	\$	1,700		\$1,530 per year		\$1,445 per year	
Government Agency	\$	2,400		\$2,160 per year		\$2,040 per year	

Standards Subscription Customer			
Annual Revenue	1 Year Membership	2 Year Membership (10% discount)	3 Year Membership (15% discount)
<\$1M	\$2,000.00	\$1,800 per year	\$1,700 per year
\$1M - <\$5M	\$2,500.00	\$2,250 per year	\$2,150 per year
\$5M - <\$25M	\$3,000.00	\$2,700 per year	\$2,550 per year
\$25M - <\$50M	\$3,500.00	\$3,150 per year	\$2,975 per year
\$50M - <\$100M	\$4,000.00	\$3,600 per year	\$3,400 per year
\$100M - <\$250M	\$5,000.00	\$4,500 per year	\$4,250 per year
\$250M - <\$500M	\$6,000.00	\$5,400 per year	□ \$5,100 per year
\$500M - <\$1B	\$7,000.00	\$6,300 per year	□ \$5,950 per year
\$1B - <\$2.5B	\$10,000.00	\$9,000 per year	\$8,500 per year
\$2.5B+	\$15,000.00	\$13,500 per year	\$12,750 per year
Government Agency	\$5,000.00	\$4,500 per year	\$4,250 per year
Education Institution	\$3,500.00	\$3,150 per year	\$2,975 per year

Company Membership — IPC's company membership provides core benefits to all employees at all of your locations.

- A free single-user download(s) of each new or revised IPC standard within 90 days of publication. (Number of free copies vary based on revenue level, see https://www.ipc.org/ipc-member-standards-benefit for details).
- Up to 50% discount on IPC standards, publications, training materials, software, events, and education
- Advocacy updates and events, including policy maker visits to your location
- Free access for all employees to periodic member only webcasts led by industry experts
- 24/7 online access to members-only resources
- · Brand-building tools

Standards Subscription Membership — All company membership benefits listed above, but for those customers who are purchasing a subscription for online access to IPC standards documents through a third-party subscription provider (separate charges apply)

* Multi-year discounts only apply when all years are purchased on the same order

PAYMENT INFORMATION: Please send payment remit to AR@ipc.org

Make all checks payable to: IPC International, Inc. 3491 Eagle Way Chicago, IL 60678-1349

USD WIRE TRANSFER: JP Morgan Chase Bank, N.A. New York, NY I SWIFT CHASUS33 I Acc# 0018231861 I ABA RTN# 021000021

EUR WIRE TRANSFER: JP Morgan Chase Bank, N.A. London I SWIFT CHASGB2L I Acc# 0077104001 I IBAN GB32 CHAS 6092 4277 1040 01

ACH: JP Morgan Chase 120 South LaSalle St. Chicago, IL 60603 | Acc# 0018231861 | ABA RTN# 071000013

To pay by credit card, fill out the application and pay online at www.ipc.org/application.

Thank you for your application!



Experience \$BENEFITS





Expand your company's resources and influence in the electronics industry.

- Stay Current
- Get Connected
- Shape the Industry
- Train Your Staff
- Contain Costs
- Join the leaders in IPC
- Market Your Business

Learn more about IPC membership and apply online at www.ipc.org/membership or contact the Member Success team at membership@ipc.org.



BUILD ELECTRONICS BETTER

3000 Lakeside Drive, Suite 105 N Bannockburn, IL 60015 USA +1 847-615-7100 **tel** +1 847-615-7105 **fax** www.**ipc**.org ISBN #978-1-63816-018-2